



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Uwe Krueger et al.                      Art Unit : 2123  
Serial No. : 09/815,274                              Examiner : Ayal I. Sharon  
Filed : March 23, 2001  
Title : MULTIVARIATE STATISTICAL PROCESS MONITORS

**MAIL STOP AMENDMENT**

Commissioner for Patents  
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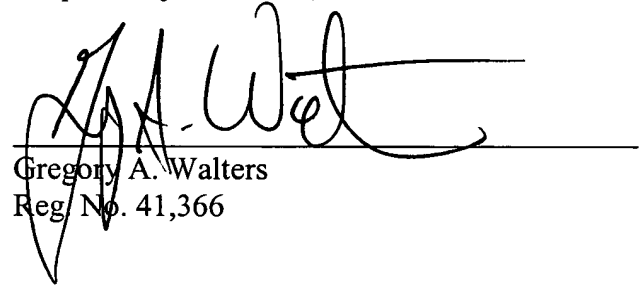
INFORMATION DISCLOSURE STATEMENT

Copies of the references listed on the attached form PTO-1449 are enclosed.

This statement is being filed after a first Office action on the merits, but before receipt of a final Office action or a Notice of Allowance. A check for \$180 in payment of the late submission fee of §1.17(p) is enclosed. Please apply any other charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: NOVEMBER 24, 2004

  
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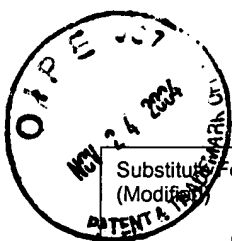
Substitute Form PTO-1449 (Required)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 15811-002001	Application No. 09/815,274
<b>Information Disclosure Statement by Applicant</b> (Use several sheets if necessary)  (37 CFR §1.98(b))		Applicant Uwe Krueger et al.	
		Filing Date March 23, 2001	Group Art Unit 2123

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	5,602,755	02/11/1997	Ashe et al.			
	AB	5,699,269	12/16/1997	Ashe et al.			
	AC	5,699,270	12/16/1997	Ashe et al.			

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AD							
	AE							

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
	AF	Q. Chen et al., "The Application of Principal Component Analysis and Kernel Density Estimation to Enhance Process Monitoring", <i>Journal Control Engineering Practice</i> , No. 8, pp. 531-543, (2000)
	AG	R. Dunia et al., "Identification of Faulty Sensors Using Principal Component Analysis", <i>AIChE Journal</i> , Vol. 42, No. 10, pp. 2797-2812, (1996)
	AH	R.C. McFarlane et al., "Dynamic Simulator For a Model IV Fluid Catalytic Cracking Unit", <i>Computers in Chemical Engineering</i> , Vol. 17, No. 3, pp. 275-300 (1993)
	AI	P. Geladi et al., "Partial Least-Squares Regression: A Tutorial", <i>Analytica Chimica Acta</i> , Vol. 185, pp. 1-17, (1986)
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	AK	A. Hoskuldsson, "PLS Regression Methods", <i>Journal of Chemometrics</i> , Vol. 2, pp. 211-228, (1988)
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	AN	T. Kourti et al., "Process Analysis, Monitoring and Diagnosis, Using Multivariate Projection" Methods, <i>Chemometrics and Intelligent Laboratory Systems</i> , Vol. 28, pp. 3-21, (1995)
	AO	J. V. Kresta et al., "Multivariate Statistical Monitoring of Process Operating Performance", <i>The Canadian Journal of Chemical Engineering</i> , Vol. 69, pp. 35-47, (1991)
	AP	F. Lindgren et al., "The Kernel Algorithm for PLS", <i>Journal of Chemometrics</i> , Vol. 7, pp. 45-59 (1993)
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	AR	T.E. Morud, "Multivariate Statistical Process Control; Example From the Chemical Process Industry", <i>Journal of Chemometrics</i> , Vol. 10, pp. 669-675 (1996)

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	



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Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
	AS	I. Nimmo, "Adequately Address Abnormal Operations", <i>Chemical Engineering Progress</i> , Vol. 91, No. 1, pp. 36-45 (1995)
	AT	P. Nomikos et al., "Multi-way Partial Least Squares in Monitoring Batch Processes", <i>Chemometrics and Intelligent Laboratory Systems</i> , Vol. 30, pp. 97-108, (1995)
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	AV	R. Manne, "Analysis of Two Partial-Least-Squares Algorithms for Multivariate Calibration," <i>Chemometrics and Intelligent Laboratory Systems</i> , Vol. 2, pp. 187-197 (1987)
	AW	M. J. Piovoso et al., "Process Data Chemometrics", <i>IEEE Transactions on Instrumentation and Measurement</i> , Vol. 41, No. 2 pp. 262-268 (1992)
	AX	B. M. Wise, "The Process Chemometrics Approach to Process Monitoring and Fault Detection", <i>Journal of Process Control</i> , Vol. 6, No. 6, pp. 329-348 (1996)
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	AZ	S. Wold, "Cross-Validatory Estimation of the Number of Components in Factor and Principal Components Models", <i>Technometrics</i> , Vol. 20, No. 4, pp. 397-405, (1978)
	AAA	U. Krger et al., "On the Application of Non-Linear Partial Least Squares to Industrial Process Control", DYMAC Conference, (1999)

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